

FCC & IC REPORT

(LTE)

Applicant: COPPERNIC
Address of Applicant: 185 avenue Archimede, 13857 Aix en Provence, FRANCE
Equipment Under Test (EUT)
Product Name: C-One HF iClass / LF Prox
Model No.: C-One HLF HID
Trade mark: COPPERNIC
FCC ID: XGK-C-ONE-HLF-HID
Canada IC: 8402A-CONEHLFHID
Applicable standards: FCC CFR Title 47 Part 2
FCC CFR Title 47 Part 22 Subpart H
FCC CFR Title 47 Part 27 Subpart M
RSS-Gen Issue 5, March 2019 Amendment 1
RSS-132 Issue 3, January 2013
RSS-199 Issue 3, December 2016
Date of sample receipt: 11 Nov., 2019
Date of Test: 12 Nov., 2019 to 02 Apr., 2020
Date of report issued: 16 Jun., 2020
Test Result: PASS*

*In the configuration tested, the EUT complied with the standards specified above.

Authorized Signature:

A circular blue ink stamp from Shenzhen Zhongjian Nanfang Testing Co., Ltd. (CCIS) is visible. Overlaid on the stamp is a handwritten signature in blue ink, which appears to read 'Bruce Zhang'.

Bruce Zhang
Laboratory Manager

This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the CCIS product certification mark. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.

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2. Version

Version No.	Date	Description
00	30 Apr., 2020	Original
01	12 Jun., 2020	Update page 4
02	16 Jun., 2020	Update Model No

Tested by:

Carey Chen

Test Engineer

Date:

16 Jun., 2020

Reviewed by:

Winner Zhang

Project Engineer

Date:

16 Jun., 2020

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4. Test Summary

Test Items	Section		Result
	FCC	IC	
RF Exposure (SAR)	Part 1.1307 Part 2.1093	RSS-102	Passed (Please refer to SAR Report)
RF Output Power	Part 2.1046 Part 22.913 (a)(5) Part 27.50 (h)(2)	RSS-Gen Section 6.12 RSS-132 section 5.4 RSS-199 section 4.4	Pass*
Peak-to-Average Ratio	Part 27.50(d)(5)	RSS-132 section 5.4 RSS-199 section 4.4	Pass*
Modulation Characteristics	Part 2.1047	RSS-132 section 5.2 RSS-199 section 4.1	Pass*
99% & -26 dB Occupied Bandwidth	Part 2.1049 Part 22.917(b) Part 27.53(m)	RSS Gen section 6.6	Pass*
Out of band emission at antenna terminals	Part 2.1051 Part 22.917(a) Part 27.53(m)	RSS-Gen section 6.13 RSS-132 section 5.5 RSS-199 section 4.5	Pass*
Field strength of spurious radiation	Part 2.1053 Part 22.917(a) Part 27.53(m)	RSS-Gen section 6.13 RSS-132 section 5.5 RSS-199 section 4.5	Pass*
Frequency stability vs. temperature	Part 22.355 Part 27.54 Part 2.1055(a)(1)(b)	RSS-Gen section 6.11 RSS-132 section 5.3 RSS-199 section 4.3	Pass*
Frequency stability vs. voltage	Part 22.355 Part 27.54 Part 2.1055(d)(2)	RSS-Gen section 6.11 RSS-132 section 5.3 RSS-199 section 4.3	Pass*

Note:

1. Pass*: please refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.
2. Pass*: Product FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR and another product FCC ID: XGK-C-ONE-HLF-HID, Canada IC: 8402A-CONELHFHID; Their internal structure, circuit design, layout, components and internal wiring are the same; GSM, WCDMA, LTE and BT, WiFi circuit design and antenna are also the same. The only difference is that the RFID module is different.

5. General Information

5.1 Client Information

Applicant:	COPPERNIC
Address:	185 avenue Archimede, 13857 Aix en Provence, FRANCE
Manufacturer:	ASKEY COMPUTER Corp.
Address:	10 F, N°119, JIANKANG RD., ZHONGHE DIST., New Tapei City, TAIWAN

5.2 General Description of E.U.T.

Product Name:	C-One HF iClass / LF Prox
Model No.:	C-One HLF HID
Operation Frequency range:	LTE Band 5: 824MHz-849MHz, RX: 869MHz-894MHz LTE Band 7: TX: 2500MHz-2570MHz, RX: 2620MHz-2690MHz
Modulation type:	QPSK, 16QAM
Antenna type:	Internal Antenna
Antenna gain:	LTE Band 5: -5.07dBi LTE Band 7: 2.32dBi
Power supply:	Rechargeable Li-ion Battery DC3.7V-3300mAh
AC adapter:	Model: SYS1561-1105-1 Input: AC100-240V, 50/60Hz, 1A Output: DC 5.35V, 2A
Test Sample Condition:	The test samples were provided in good working order with no visible defects.

Operation Frequency List:

LTE Band 5 (1.4MHz)		LTE Band 5 (3MHz)	
Channel	Frequency (MHz)	Channel	Frequency (MHz)
20407	824.70	20415	825.50
20408	824.80	20416	825.60
....			
20524	836.40	20524	836.40
20525	836.50	20525	836.50
20526	836.60	20526	836.60
...	...	...	...
20642	848.20	20634	847.40
20643	848.30	20635	847.50
LTE Band 5 (5MHz)		LTE Band 5 (10MHz)	
Channel	Frequency (MHz)	Channel	Frequency (MHz)
20425	826.50	20450	829.00
20426	826.60	20451	829.10
....			
20524	836.40	20524	836.40
20525	836.50	20525	836.50
20526	836.60	20526	836.60
...	...	...	...
20624	846.40	20599	839.90
20625	846.50	20600	844.00

LTE Band 7 (5MHz)		LTE Band 7 (10MHz)	
Channel	Frequency (MHz)	Channel	Frequency (MHz)
20775	2502.50	20800	2505.00
20776	2502.60	20801	2502.10
....			
21099	2534.90	21099	2534.90
21100	2535.00	21100	2535.00
21101	2535.20	21101	2535.20
...	...	...	...
21424	2567.40	21399	2564.90
21425	2567.50	21400	2565.00
LTE Band 7 (15MHz)		LTE Band 7 (20MHz)	
Channel	Frequency (MHz)	Channel	Frequency (MHz)
20825	2507.50	20850	2510.00
20826	2507.60	20851	2510.10
....			
21099	2534.90	21099	2534.90
21100	2535.00	21100	2535.00
21101	2535.20	21101	2535.20
...	...	...	...
21374	2562.40	21349	2559.90
21375	2562.50	21350	2560.00

Regards to the operating frequency range, the lowest frequency, the middle frequency, and the highest frequency of channel were selected to perform the test, and the selected channels as below:

LTE Band 5 (1.4MHz)			LTE Band 5 (3MHz)		
Channel:		Frequency (MHz)	Channel		Frequency (MHz)
Lowest channel	20407	824.70	Lowest channel	20415	825.50
Middle channel	20525	836.50	Middle channel	20525	836.50
Highest channel	20643	848.30	Highest channel	20635	847.50
LTE Band 5 (5MHz)			LTE Band 5 (10MHz)		
Channel		Frequency (MHz)	Channel		Frequency (MHz)
Lowest channel	20425	826.50	Lowest channel	20450	829.00
Middle channel	20525	836.50	Middle channel	20525	836.50
Highest channel	20625	846.50	Highest channel	20600	844.00

LTE Band 7 (5MHz)			LTE Band 7 (10MHz)		
Channel		Frequency (MHz)	Channel		Frequency (MHz)
Lowest channel	20775	2502.50	Lowest channel	20800	2505.00
Middle channel	21100	2535.00	Middle channel	21100	2535.00
Highest channel	21425	2567.50	Highest channel	21400	2565.00
LTE Band 7 (15MHz)			LTE Band 7 (20MHz)		
Channel		Frequency (MHz)	Channel		Frequency (MHz)
Lowest channel	20825	2507.50	Lowest channel	20850	2510.00
Middle channel	21100	2535.00	Middle channel	21100	2535.00
Highest channel	21375	2562.50	Highest channel	21350	2560.00

5.3 Test environment and mode

Operating Environment:	
Temperature:	Normal: 15°C ~ 35°C, Extreme: -30°C ~ +50°C
Humidity:	20 % ~ 75 % RH
Atmospheric Pressure:	1008 mbar
Voltage:	Nominal: 3.7Vdc, Extreme: Low 3.5Vdc, High 4.2Vdc
Test mode:	
LTE QPSK mode	Keep the EUT communication with simulated station in QPSK mode
LTE 16-QAM mode	Keep the EUT communication with simulated station in 16-QAM mode
Remark: The EUT has been tested under continuous transmitting mode. Channel Low, Mid and High for each type band with rated data rate were chosen for full testing. The field strength of spurious radiation emission was measured as EUT stand-up position (H mode) and lie down position (E1, E2 mode) for these modes with power adaptor, earphone and Data cable. Just the worst case position (H mode) shown in report.	

5.4 Description of Support Units

Test Equipment	Manufacturer	Model No.	Serial No.
Simulated Station	Anritsu	MT8820C	6201026545

5.5 Measurement Uncertainty

Parameters	Expanded Uncertainty
Radiated Emission (9kHz ~ 30MHz)	±3.12 dB (k=2)
Radiated Emission (30MHz ~ 1000MHz)	±4.32 dB (k=2)
Radiated Emission (1GHz ~ 18GHz)	±5.38 dB (k=2)
Radiated Emission (18GHz ~ 40GHz)	±3.36 dB (k=2)

5.6 Related Submittal(s) / Grant (s)

This is an original grant, no related submittals and grants.

5.7 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

● **FCC - Designation No.: CN1211**

Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been accredited as a testing laboratory by FCC(Federal Communications Commission). The test firm Registration No. is 727551.

● **ISED – CAB identifier.: CN0021**

The 3m Semi-anechoic chamber of Shenzhen Zhongjian Nanfang Testing Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 10106A-1.

● **A2LA - Registration No.: 4346.01**

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. The test scope can be found as below link: <https://portal.a2la.org/scopepdf/4346-01.pdf>

5.8 Laboratory Location

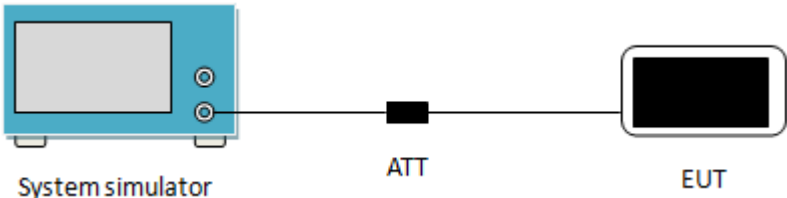
Shenzhen Zhongjian Nanfang Testing Co., Ltd.
 Address: No.110~116, Building B, Jinyuan Business Building, Xixiang Road,
 Bao'an District, Shenzhen, Guangdong, China
 Tel: +86-755-23118282, Fax: +86-755-23116366
 Email: info@ccis-cb.com, Website: <http://www.ccis-cb.com>

5.9 Test Instruments list

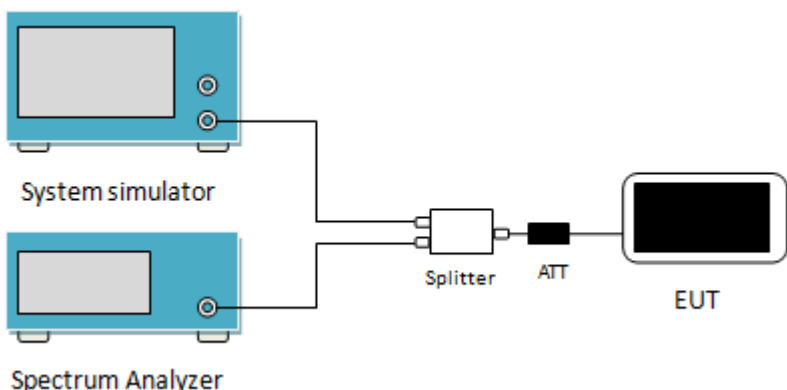
Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (mm-dd-yy)	Cal. Due date (mm-dd-yy)
3m SAC	SAEMC	9m*6m*6m	966	07-22-2017	07-21-2020
BiConiLog Antenna	SCHWARZBECK	VULB9163	497	03-18-2019	03-17-2020
Biconical Antenna	SCHWARZBECK	VUBA9117	359	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA9120D	916	03-18-2019	03-17-2020
Horn Antenna	SCHWARZBECK	BBHA9120D	1805	06-22-2017	06-21-2020
Horn Antenna	SCHWARZBECK	BBHA 9170	BBHA9170582	11-18-2018	11-17-2019
				11-18-2019	11-17-2020
EMI Test Software	AUDIX	E3	Version: 6.110919b		
Pre-amplifier	HP	8447D	2944A09358	03-18-2019	03-17-2020
Pre-amplifier	CD	PAP-1G18	11804	03-18-2019	03-17-2020
Spectrum analyzer	Rohde & Schwarz	FSP30	101454	03-18-2019	03-17-2020
				03-18-2020	03-17-2021
EMI Test Receiver	Rohde & Schwarz	ESRP7	101070	03-18-2019	03-17-2020
Spectrum Analyzer	Agilent	N9020A	MY50510123	11-18-2018	11-17-2019
				11-18-2019	11-17-2020
Signal Generator	Rohde & Schwarz	SMX	835454/016	03-18-2019	03-17-2020
Signal Generator	R&S	SMR20	1008100050	03-18-2019	03-17-2020
RF Switch Unit	MWRFTTEST	MW200	N/A	N/A	N/A
Test Software	MWRFTTEST	MTS8200	Version: 2.0.0.0		
Cable	ZDECL	Z108-NJ-NJ-81	1608458	03-18-2019	03-17-2020
Cable	MICRO-COAX	MFR64639	K10742-5	03-18-2019	03-17-2020
Cable	SUHNER	SUCOFLEX100	58193/4PE	03-18-2019	03-17-2020
DC Power Supply	XinNuoEr	WYK-10020K	1409050110020	09-25-2019	09-24-2020
Temperature Humidity Chamber	HengPu	HPGDS-500	20140828008	11-01-2019	10-31-2020
Simulated Station	Rohde & Schwarz	CMW500	140493	07-22-2019	07-21-2020

6. Test results

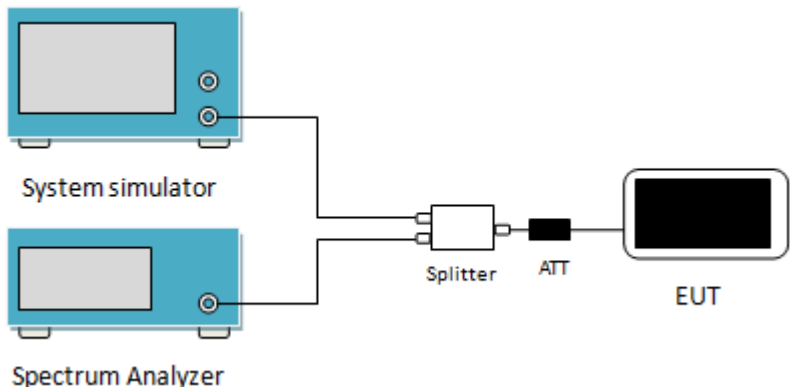
6.1 Conducted Output Power, ERP and EIRP

Test Requirement:	Part 22.913(a)(5), Part 27.50 (h)(2) RSS-132 section 5.4, RSS-199 section 4.4
Test Method:	ANSI/TIA-603-D 2010
Limit:	FCC: LTE Band 5: 7W, LTE Band 7: 2W, IC: LTE Band 5: 11.5W, LTE Band 7: 2W,
Test Setup:	 The diagram illustrates the test setup. On the left is a blue 'System simulator' with a screen and two ports. A line connects it to a black 'ATT' (attenuator) block. Another line connects the 'ATT' to a black 'EUT' (Equipment Under Test) device on the right.
Test Procedure:	The transmitter output was connected to a calibrated attenuator, the other end of which was connected to the CMW500. Transmitter output power was read off in dBm.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

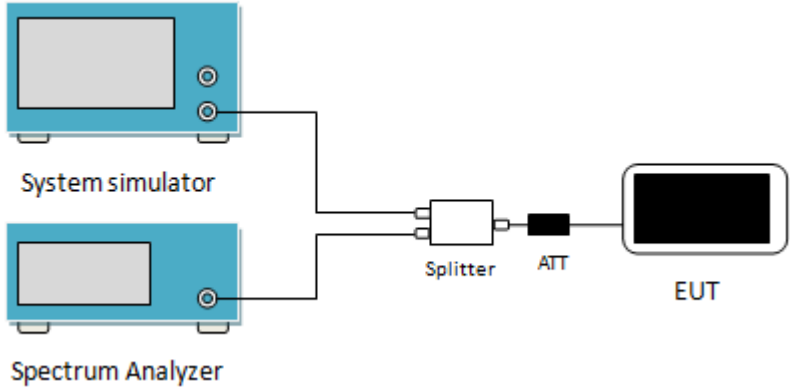
6.2 Peak-to-Average Ratio

Test Requirement:	Part 27.50(d)(5) RSS-132 section 5.4, RSS-199 section 4.4
Test Method:	ANSI/TIA-603-D 2010
Limit:	The peak-to-average ratio (PAR) of the transmission may not exceed 13 dB.
Test Setup:	 The diagram illustrates the test setup. On the left, there are two blue rectangular units: the top one is labeled 'System simulator' and the bottom one is labeled 'Spectrum Analyzer'. Both have two circular ports on their right side. A single line connects the top port of the System simulator to the top port of the Spectrum Analyzer. From the bottom port of the System simulator, a line goes to the top port of a white rectangular unit labeled 'Splitter'. From the bottom port of the Spectrum Analyzer, a line goes to the bottom port of the 'Splitter'. The 'Splitter' has two output ports on its right side. The top output port is connected to a black rectangular unit labeled 'ATT' (attenuator). The bottom output port is connected to a black rectangular unit labeled 'EUT' (Equipment Under Test).
Test Procedure:	1 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. 2 Set the CCDF option in spectrum analyzer, RBW $\geq$ OBW, 3 Set the EUT working in highest power level, measured and recorded the 0.1% as PAPR level. 4 Repeat step 1~3 at other frequency and modulations.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

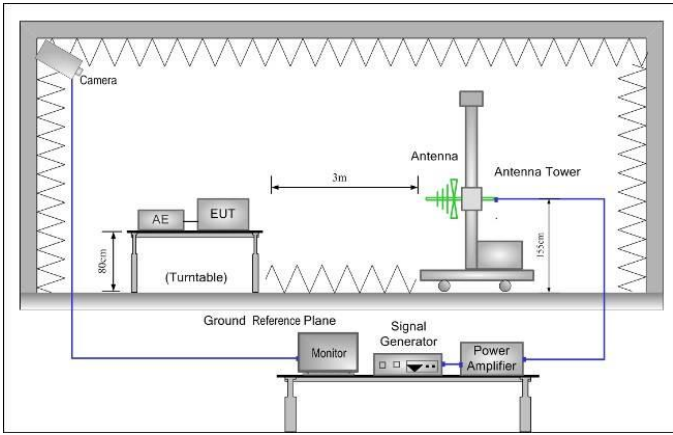
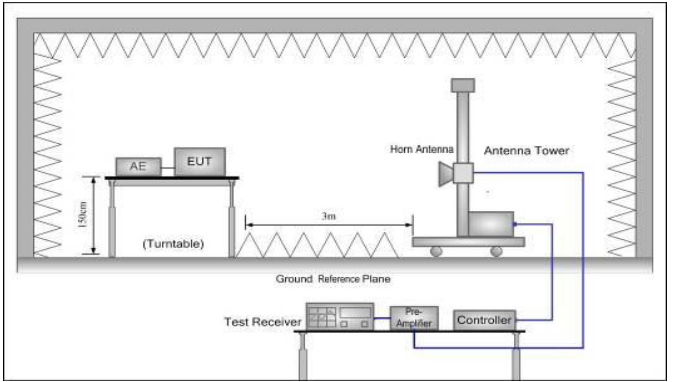
6.3 Occupy Bandwidth

Test Requirement:	Part 22.917(b), Part 27.53(m), RSS-GEN section 6.6
Test Method:	RSS-GEN section 6.6, ANSI/TIA-603-D 2010
Test Setup:	 The diagram illustrates the test setup. On the left, there are two blue rectangular devices: a 'System simulator' on top and a 'Spectrum Analyzer' on the bottom. Both have two circular ports on their right side. A single cable connects the top port of the System simulator to the top port of the Spectrum Analyzer. From the bottom port of the Spectrum Analyzer, a cable goes to a 'Splitter' (a small white rectangle with two ports). The other output of the Splitter goes to an 'ATT' (Attenuator, a small black rectangle). Finally, a cable connects the ATT to the 'EUT' (Equipment Under Test, represented by a black rectangle with a white border).
Test Procedure:	1. The EUT's output RF connector was connected with a short cable to the spectrum analyzer 2. RBW was set to about 1% ~ 5% of emission BW, VBW= 3 times RBW. 3. -26dBc display line was placed on the screen (or 99% bandwidth), the occupied bandwidth is the delta frequency between the two points where the display line intersects the signal trace.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

6.4 Out of band emission at antenna terminals

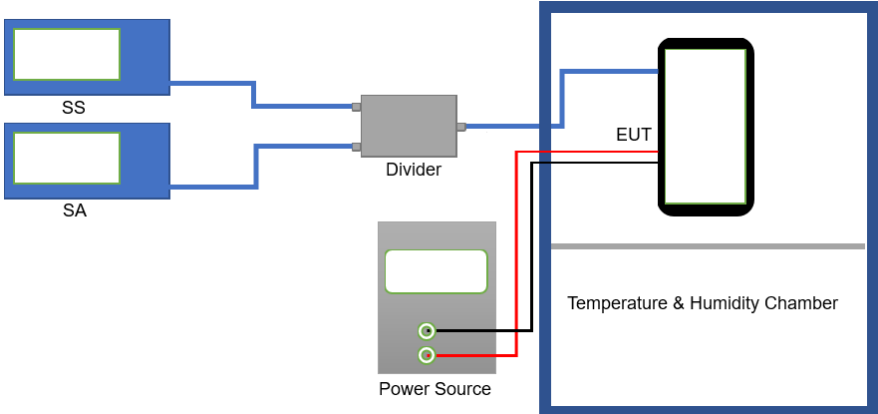
Test Requirement:	Part 22.917(b), Part 27.53(m) RSS-132 section 5.5, , RSS-199 section 4.5
Test Method:	RSS-GEN section 6.13, ANSI/TIA-603-D 2010
Limit:	LTE Band 5: The power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) in watts by at least $43 + 10 \log_{10}(P)$ dB (-13 dBm). LTE Band 7: For mobile digital stations, the attenuation factor shall be not less than $40 + 10 \log(P)$ dB on all frequencies between the channel edge and 5 megahertz from the channel edge, $43 + 10 \log(P)$ dB on all frequencies between 5 megahertz and X megahertz from the channel edge, and $55 + 10 \log(P)$ dB on all frequencies more than X megahertz from the channel edge, where X is the greater of 6 megahertz or the actual emission bandwidth as defined in paragraph (m)(6) of this section. In addition, the attenuation factor shall not be less than $43 + 10 \log(P)$ dB on all frequencies between 2490.5 MHz and 2496 MHz and $55 + 10 \log(P)$ dB at or below 2490.5 MHz.
Test Setup:	 The diagram illustrates the test setup. On the left, there are two blue rectangular units: the top one is labeled 'System simulator' and the bottom one is labeled 'Spectrum Analyzer'. Both have a single output port. These two ports are connected to a central 'Splitter' unit. From the Splitter, one line goes to an 'ATT' (Attenuator) unit, and another line goes to the 'EUT' (Equipment Under Test), which is represented by a black rectangular device.
Test Procedure:	1 The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. 2 The resolution bandwidth of the spectrum analyzer was set at 100 kHz when below 1GHz, 1MHz when above 1 GHz; sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. 3 For the out of band: Set the RBW=100 kHz, VBW=300 kHz when below 1 GHz, RBW =1 MHz, VBW=3 MHz when above 1 GHz, Start=30MHz, Stop= 10th harmonic. 4 Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

6.5 Field strength of spurious radiation measurement

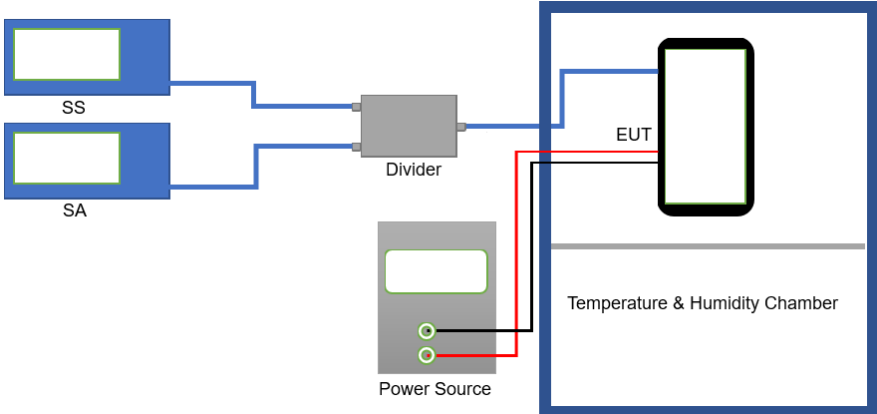
Test Requirement:	Part 22.917(b), Part 27.53(m), RSS-132 section 5.5, RSS-199 section 4.5
Test Method:	RSS-GEN section 6.13, ANSI/TIA-603-D 2010
Limit:	LTE Band 5: The power of any emission outside a licensee's frequency block shall be attenuated below the transmitter power (P) in watts by at least $43 + 10 \log_{10}(P)$ dB (-13 dBm). LTE Band 7: For mobile digital stations, the attenuation factor shall be not less than $40 + 10 \log(P)$ dB on all frequencies between the channel edge and 5 megahertz from the channel edge, $43 + 10 \log(P)$ dB on all frequencies between 5 megahertz and X megahertz from the channel edge, and $55 + 10 \log(P)$ dB on all frequencies more than X megahertz from the channel edge, where X is the greater of 6 megahertz or the actual emission bandwidth as defined in paragraph (m)(6) of this section. In addition, the attenuation factor shall not be less than $43 + 10 \log(P)$ dB on all frequencies between 2490.5 MHz and 2496 MHz and $55 + 10 \log(P)$ dB at or below 2490.5 MHz.
Test setup:	Below 1GHz  Above 1GHz 
Test Procedure:	1. The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer. 2. During the tests, the antenna height and the EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. This maximization process was repeated with the EUT positioned in each of its three orthogonal orientations. 3. The frequency range up to tenth harmonic was investigated for each

	of three fundamental frequency (low, middle and high channels). Once spurious emission was identified, the power of the emission was determined using the substitution method. 4. The spurious emissions attenuation was calculated as the difference between radiated power at the fundamental frequency and the spurious emissions frequency. ERP / EIRP = S.G. output (dBm) + Antenna Gain(dB/dBi) – Cable Loss (dB)
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details.
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

6.6 Frequency stability V.S. Temperature measurement

Test Requirement:	Part 22.355, Part 27.54, Part 2.1055(a)(1)(b) RSS-132 section 5.3, RSS-199 section 4.3
Test Method:	RSS-GEN section 6.11, ANSI/TIA-603-D 2010
Limit:	±2.5ppm
Test setup:	 The diagram illustrates the test setup. On the left, there are two blue boxes labeled 'SS' (Signal Source) and 'SA' (Spectrum Analyzer). They are connected to a central grey box labeled 'Divider'. The 'Divider' is connected to a black box labeled 'EUT' (Equipment Under Test) which is placed inside a larger blue box labeled 'Temperature & Humidity Chamber'. A 'Power Source' (grey box) is connected to the 'EUT' via red and black wires.
Test procedure:	1. The equipment under test was connected to an external DC power supply and input rated voltage. 2. RF output was connected to a frequency counter or spectrum analyzer via feed through attenuators. 3. The EUT was placed inside the temperature chamber. 4. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and measure EUT 25°C operating frequency as reference frequency. 5. Turn EUT off and set the chamber temperature to –30°C. After the temperature stabilized for approximately 30 minutes recorded the frequency. 6. Repeat step measure with 10°C increased per stage until the highest temperature of +50°C reached
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

6.7 Frequency stability V.S. Voltage measurement

Test Requirement:	Part 22.355, Part 27.54, Part 2.1055(d)(2) RSS-132 section 5.3, RSS-199 section 4.3
Test Method:	RSS-GEN section 6.11, ANSI/TIA-603-D 2010
Limit:	±2.5ppm
Test setup:	 The diagram illustrates the test setup. A Spectrum Analyzer (SA) and a Signal Source (SS) are connected to a Divider. The Divider is connected to the EUT (Equipment Under Test) inside a Temperature & Humidity Chamber. A Power Source is also connected to the EUT.
Test procedure:	1. Set chamber temperature to 25°C. Use a variable DC power source to power the EUT and set the voltage to rated voltage. 2. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. 3. Reduce the input voltage to specify extreme voltage variation (+/- 15%) and endpoint, record the maximum frequency change.
Test Instruments:	Refer to section 5.9 for details
Test mode:	Refer to section 5.3 for details
Test results:	Refer to FCC ID: XGK-C-ONE-LF-AGR, Canada IC: 8402A-CONELFAGR.

8 EUT Constructional Details

Reference to the test report No. CCISE200401601V02.

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